Product Data Sheet

Reference Material - RM

RCu 12 / 05

Copper Base (Type of Standard)
Low alloy copper setting up sample (SUS)

Indicative Values

Element	Mass fraction [%]
Zinc (Zn)	(0.2)
Lead (Pb)	(0.06)
Tin (Sn)	(0.2)
Phosphorus (P)	(0.06)
Manganese (Mn)	(0.05)
Iron (Fe)	(0.06)
Nickel (Ni)	(0.04)
Silicon (Si)	(0.08)
Magnesium (Mg)	(0.01)
Chromium (Cr)	(0.05)
Tellurium (Te)	(0.03)
Arsenic (As)	(0.09)
Selenium (Se)	(0.01)
Antimony (Sb)	(0.1)
Cadmium (Cd)	(0.02)
Bismuth (Bi)	(0.01)
Silver (Ag)	(0.01)
Cobalt (Co)	(0.06)
Aluminium (Al)	(0.008)
Sulfur (S)	(0.02)
Zirconium (Zr)	(0.007)
Beryllium (Be)	(< 0.001)
Titanium (Ti)	(0.01)

Values in brackets ( ) are not certified but given for information only.

Manufacturing
This setting up sample is produced by casting.

Homogeneity
Homogeneity testing is performed by means of spark emission spectroscopy. Tests involve making multiple measurements on individual samples taken from each rod. Depending on the mass fraction of the element, the relative standard deviation of 10 to 20 measurements within one disc is influenced by the material homogeneity and stability of the measurement instrument. It is typically found between 0.3% - 1.5% for Zn, Sn, Mn, Fe, Ni, Si, Cr, As, Bi, Ag, Co and Al, between 1.5% - 3.5% for P, Pb Te, Sb and Cd and between 3.5% and 6% for Mg, S, Zr, Ti and Se. Homogeneity in between discs is not guaranteed.

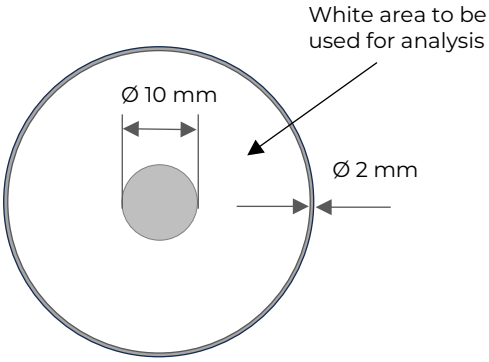
Analysis
The homogeneity analysis of this material was performed in our ISO/IEC 17025 accredited analytical laboratory (STS 0023) by spark optical emission spectroscopy. This is a setting up sample. Only homogeneity of this standard is analyzed. No mass fraction values are certified. The values given in brackets have been determined using spark source optical emission spectroscopy.

Description of Sample
This setting up sample is available in the form of discs (approx. Ø 40 x 30 mm).

Intended Use and Stability
This setting up sample is primarily intended for use in spark optical emission spectroscopy. The use in other applications such as X-ray fluorescence spectrometry (XRF) or laser induced breakdown spectroscopy (LIBS) is also possible. This reference material shall mainly be used for drift correction over time. It shall not be used for instrument calibration. The material will remain stable for the period given below (data sheet validity) if it is stored in a dry (non-condensing) and clean environment at room temperature (≤ 40 °C).

Instructions for Use

Measurements should be made within a ring (see white area in the picture). For spark OES analysis, the surface of the material needs to be prepared by milling. The minimum area to be analyzed is 30 mm^2. This reference material shall mainly be used for drift correction. The values within one disc may be regarded as constant for this purpose. For a new disc of the same material the values may slightly differ, and this should be taken into account (check operator manual of your system).



Accreditation
Suisse Technology Partners Ltd. is accredited as a producer of reference materials and certified reference materials according to ISO 17034 (SRMS 0006). This material was analyzed in our own laboratories accredited according to ISO/IEC 17025 (STS 0023). This material is a reference material which was produced outside the scope of accreditation of SRMS 0006.





Dr. Benedikt Moser
Senior Technical Advisor

Patrik Bachmann
Head of Chemical Analytics

Suisse Technology Partners Ltd.
Querstrasse 5
8212 Neuhausen am Rheinfall
Switzerland

Phone: +41 52 551 11 00
E-mail: refmat@suisse-tp.ch
Internet: https://reference-materials.ch

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This certificate
can be downloaded
here: https://refmat.ch/RCu12-05